



POLITECNICO DI MILANO

Piazza Leonardo da Vinci, 32 - 20133 Milano
Tel. +39.02.2399.1 - <http://www.polimi.it>



Advanced Course on

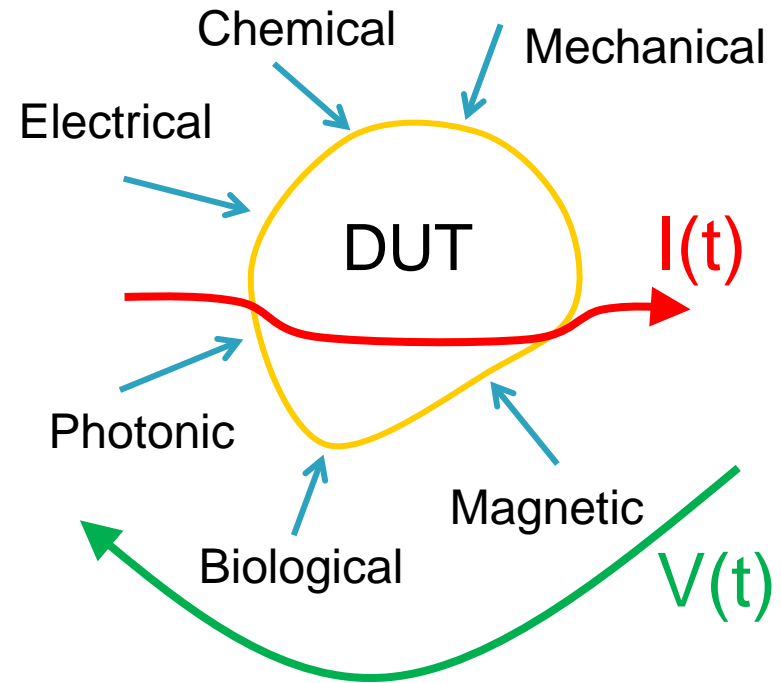
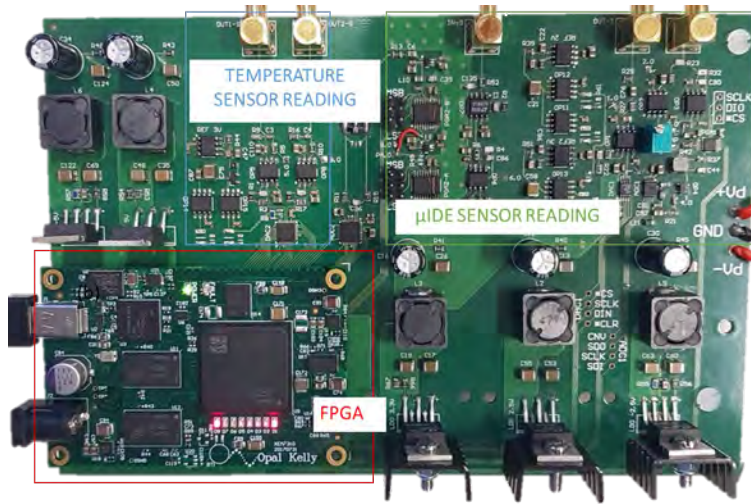
HIGH RESOLUTION ELECTRONIC MEASUREMENTS
IN NANO-BIO SCIENCE

Impedance Measurement *Architectures and performance*

Marco Sampietro



Why measuring impedance values

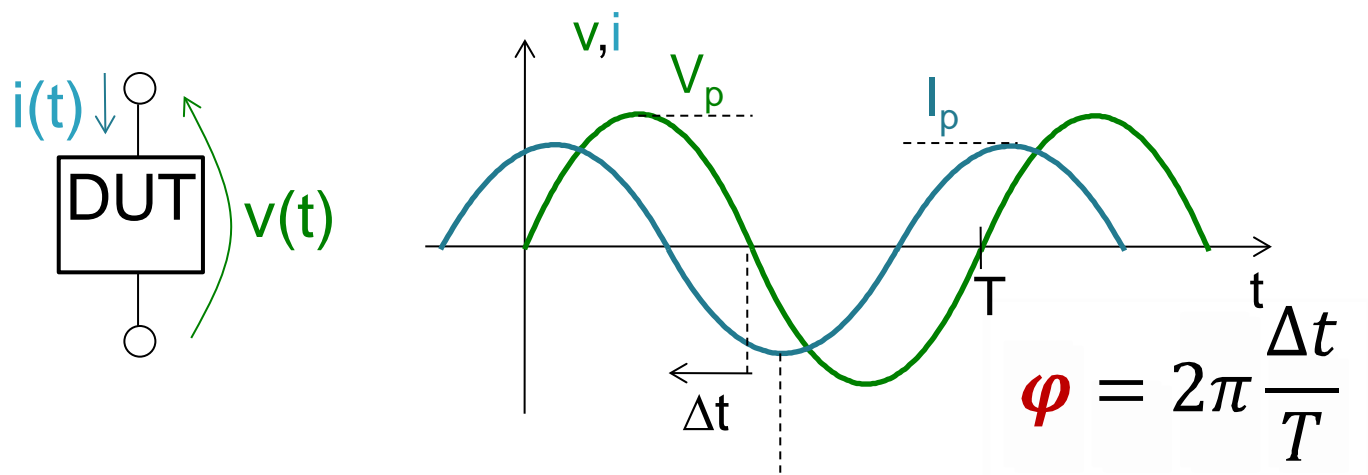


Extract R, L, C values in
an electronic circuits ...

... access the conduction
properties and the dissipative
properties of a new
device/material/molecule/etc.



Definition



Amplitude
&
Phase
&
Frequency

$\mathbf{Z} = \frac{\mathbf{V}}{\mathbf{I}}$ is a complex quantity

Impedance [Ohm]

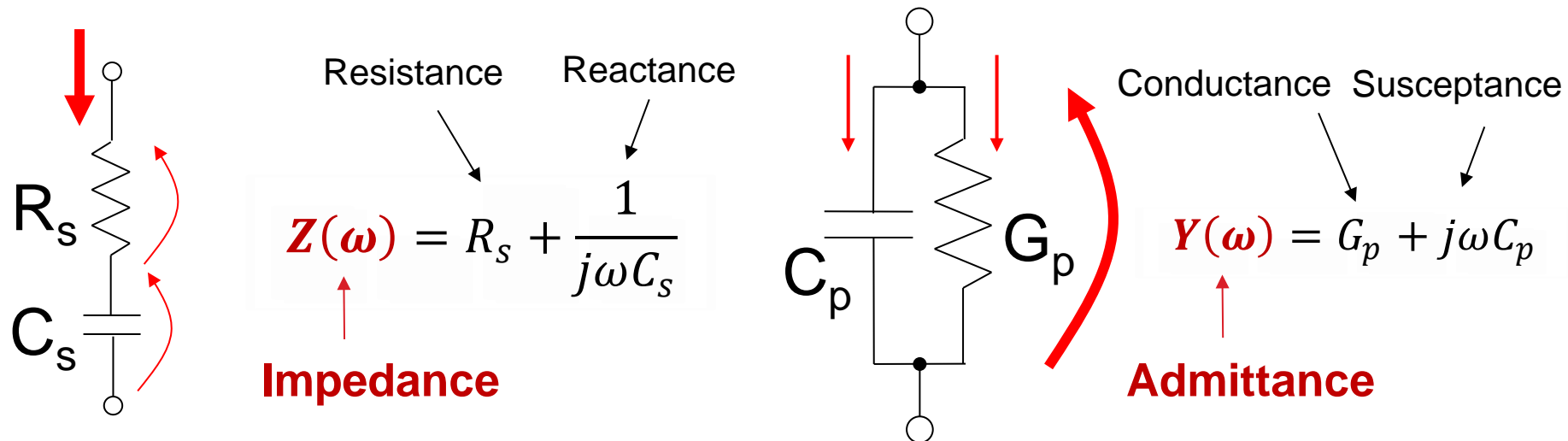


Admittance [Siemens]





Impedance in terms of single R & C

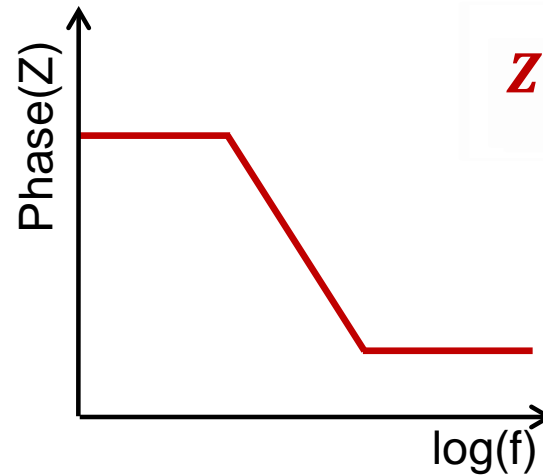
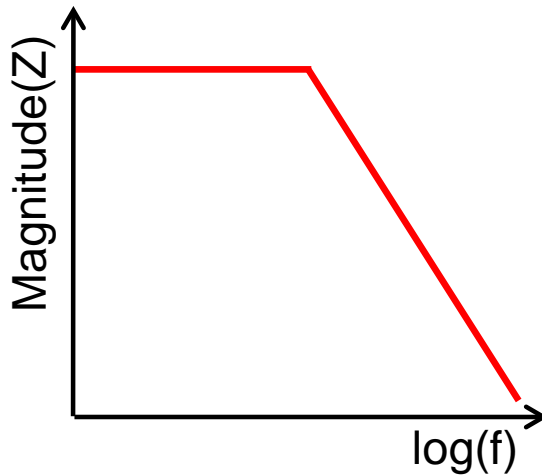


- $\text{Re}\{Z\}, \text{Re}\{Y\} \rightarrow$ **energy dissipation** ($4kT\text{Re}\{Z\}, 4kT\text{Re}\{Y\}$)
- $\text{Im}\{Z\}, \text{Im}\{Y\} \rightarrow$ **energy storage**

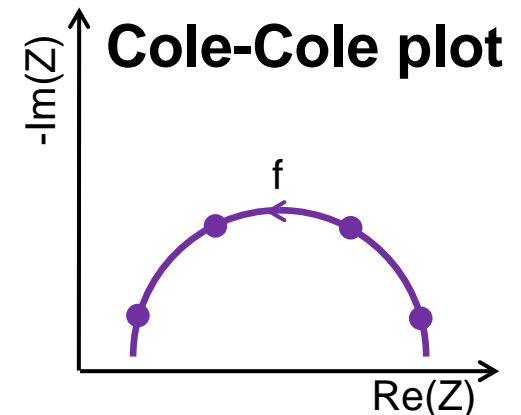
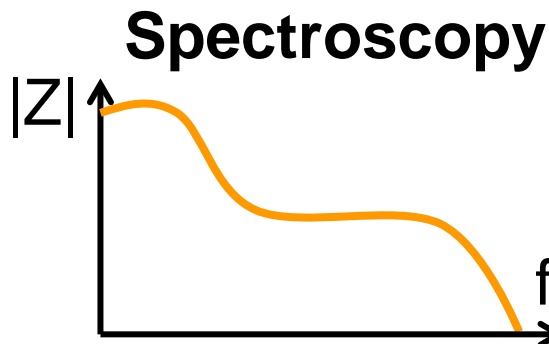
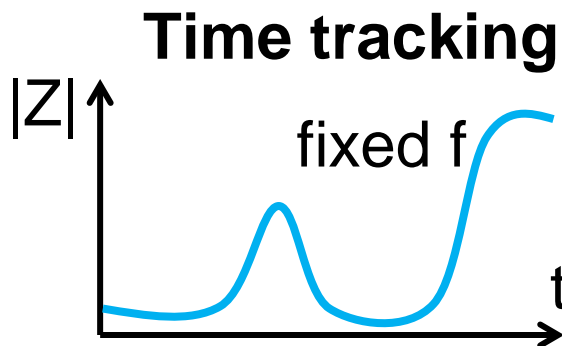
Plotting the Impedance

Equivalent ways to plot impedance / admittance values

Bode Plots



$$Z(\omega) = R_s + \frac{1}{j\omega C_s}$$





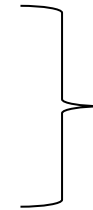
Myself : How can I measure the impedance of a device ?

chatGPT : Using an Impedance Analyzer

Using an LCR Meter

Bridge Circuit

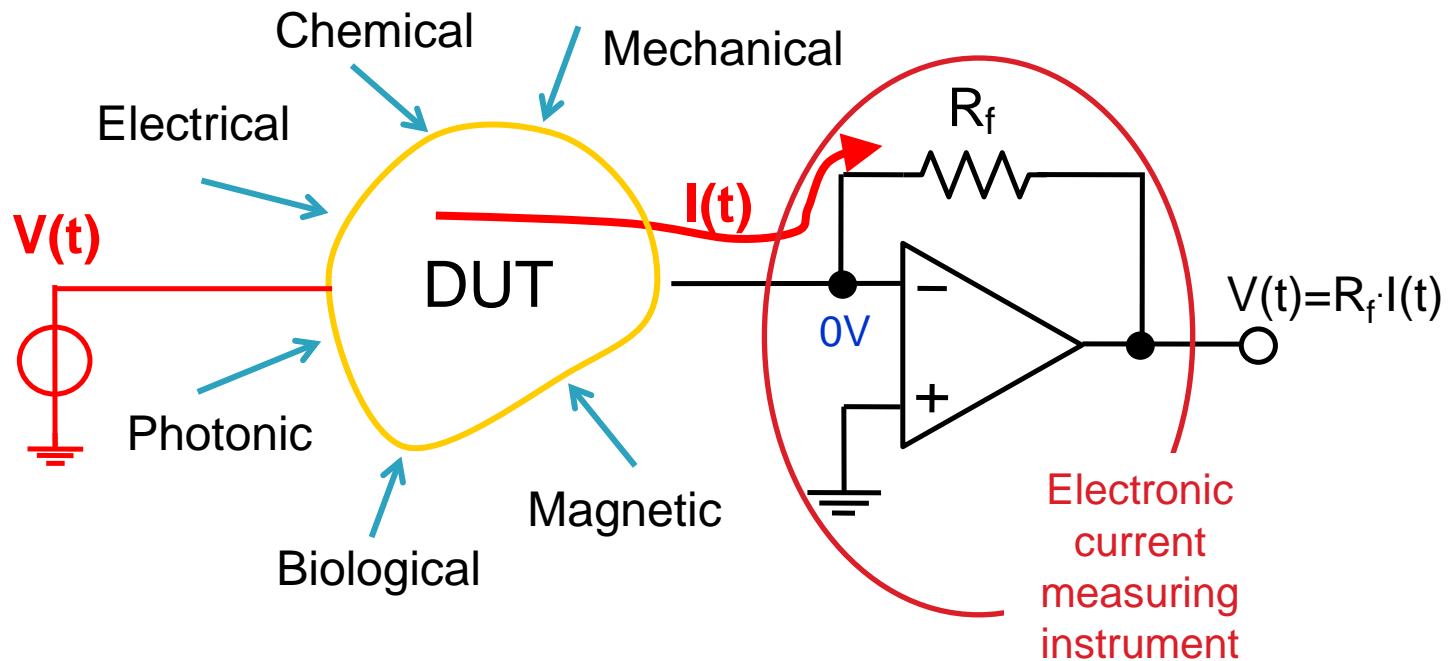
Oscilloscope and Function Generator using the voltage-divider principle



Lock-in
architecture



Lock-in configuration

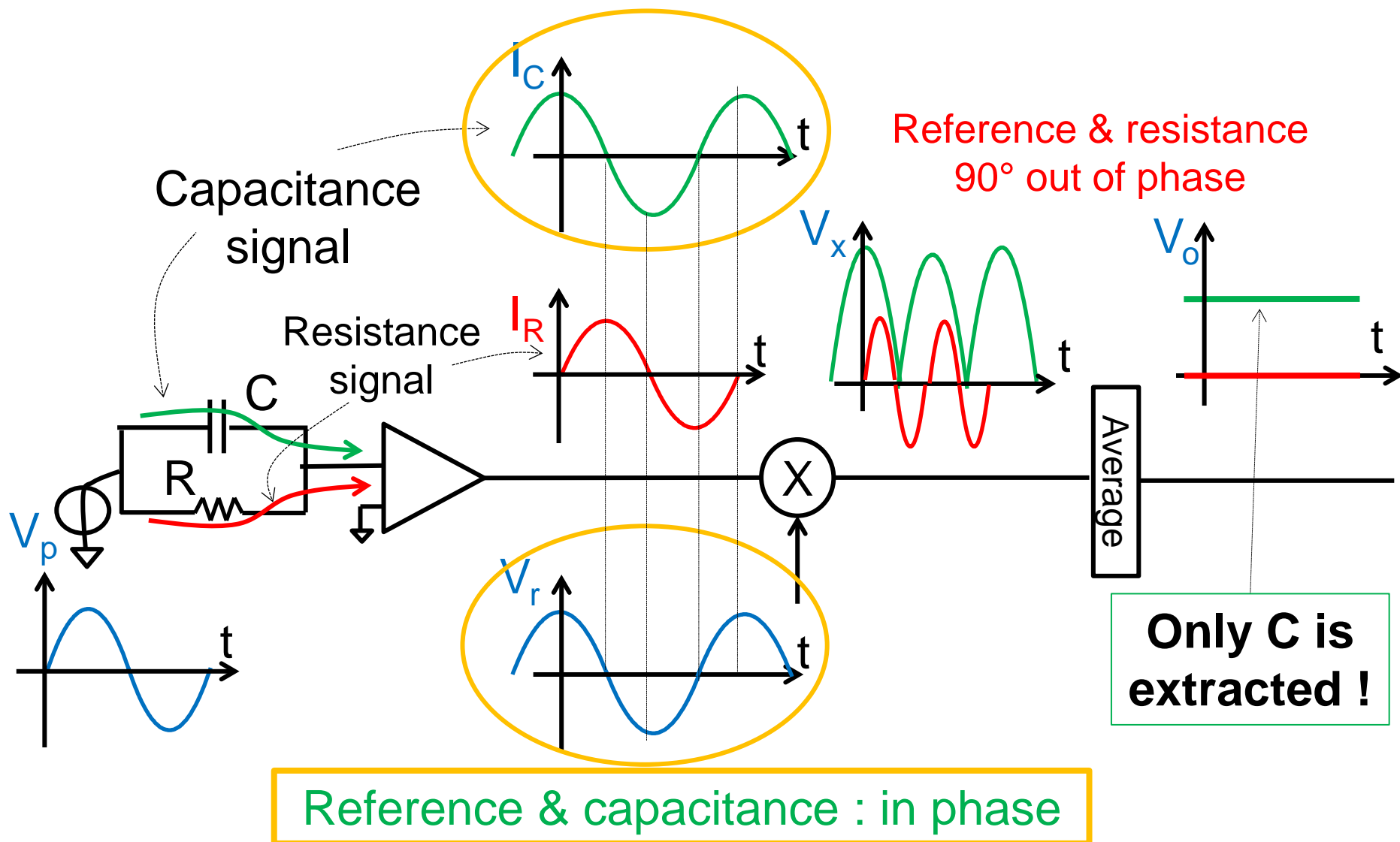


The Lock-in system is indeed ideal to perform IMPEDANCE measurements (and tracking it with time)

By sweeping the frequency, you can easily perform IMPEDANCE SPECTRUM

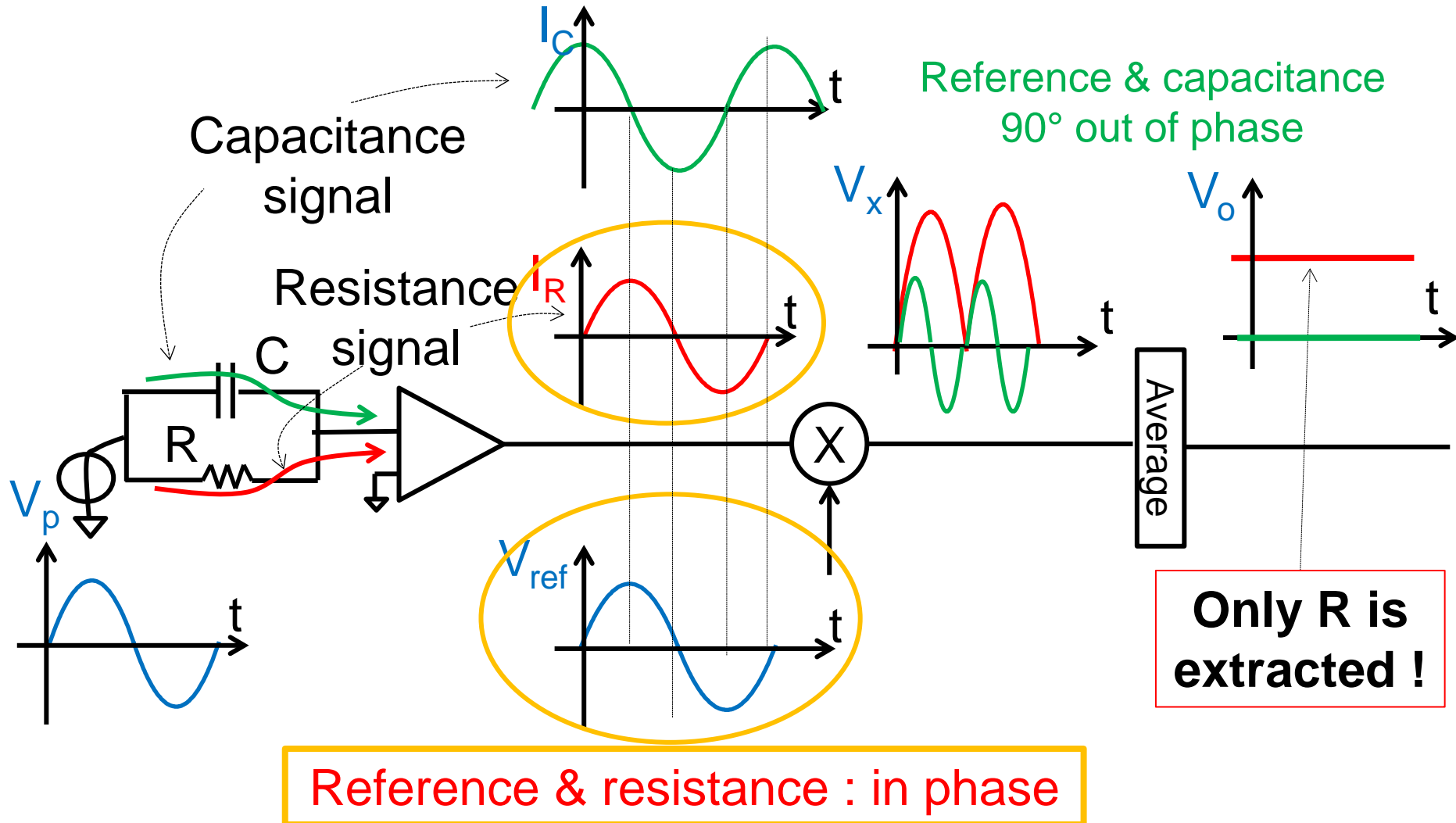


Mixture of R & C in real sensors





R & C selectivity of the LOCK-IN

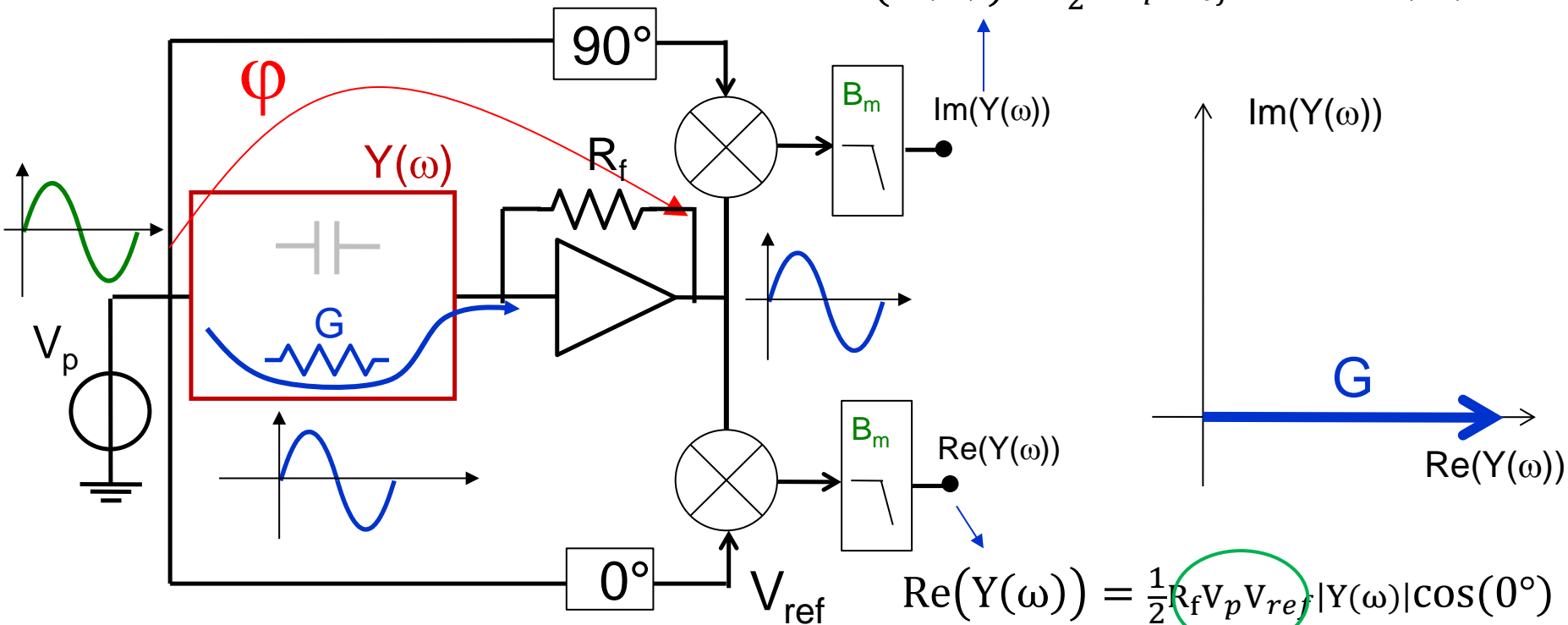




Double Lock-In: in-phase detection

Two multipliers are used to obtain both Re and Im of a DUT

$$\text{Im}(Y(\omega)) = \frac{1}{2} R_f V_p V_{ref} |Y(\omega)| \sin(0^\circ) = 0$$



$$\text{Re}(Y(\omega)) = \frac{1}{2} R_f V_p V_{ref} |Y(\omega)| \cos(0^\circ)$$

$$G = \frac{2 \cdot \text{Re}(Y(\omega))}{R_f V_p V_{ref}}$$

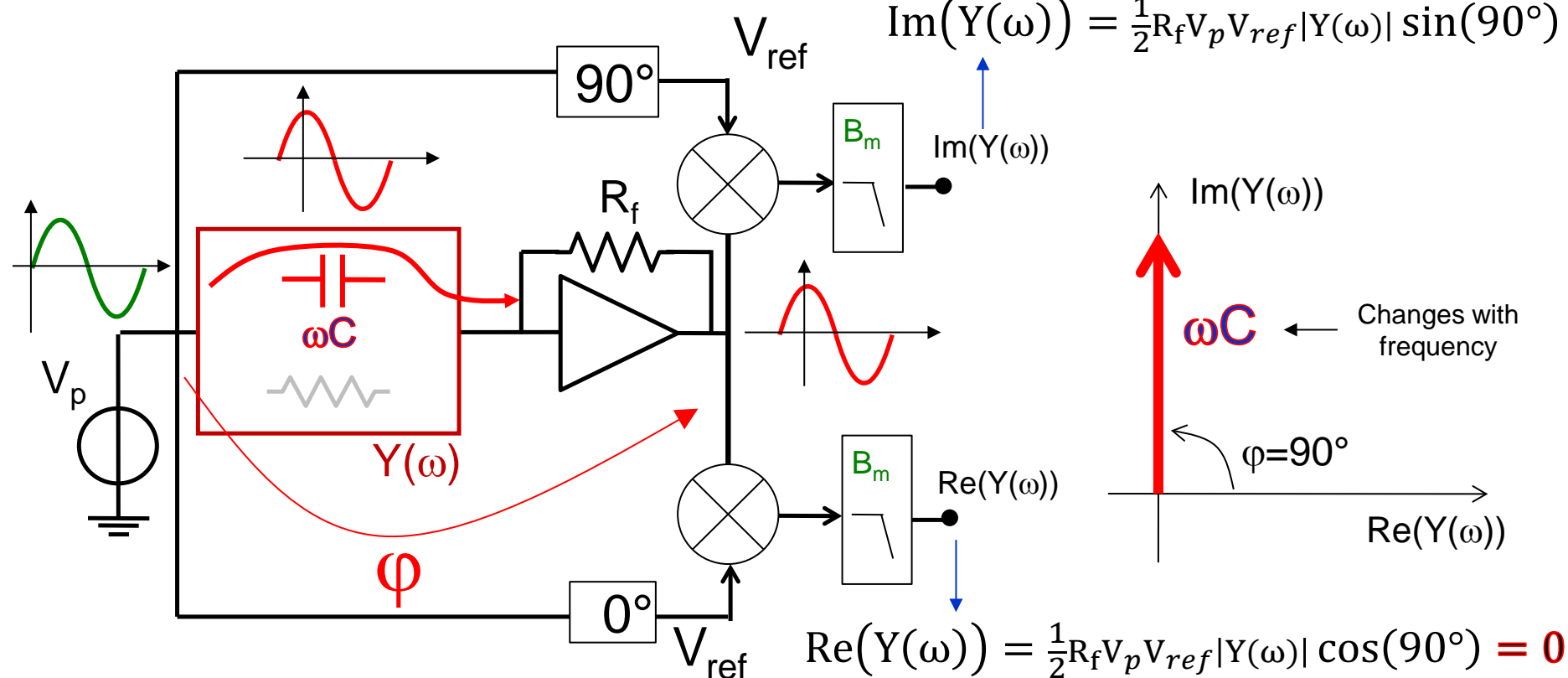


Double Lock-In: in-quadrature detect.

$$\omega C = \frac{2 \cdot \text{Im}(Y(\omega))}{R_f V_p V_{ref}}$$

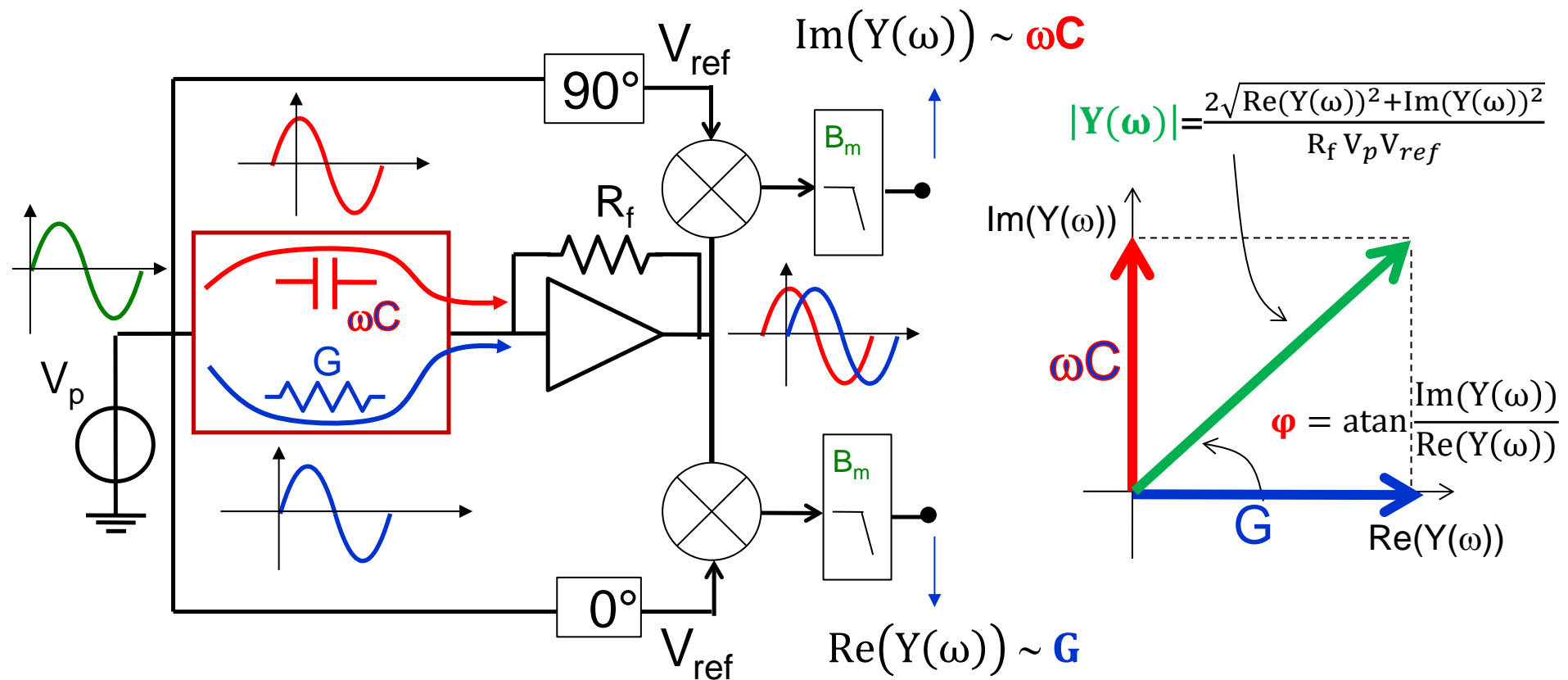


$$\text{Im}(Y(\omega)) = \frac{1}{2} R_f V_p V_{ref} |Y(\omega)| \sin(90^\circ)$$



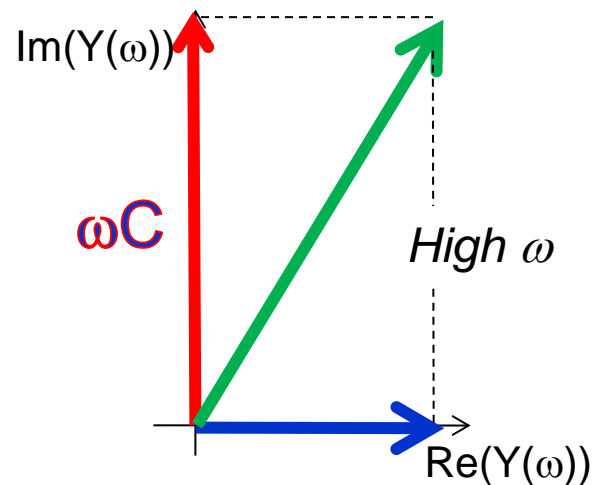
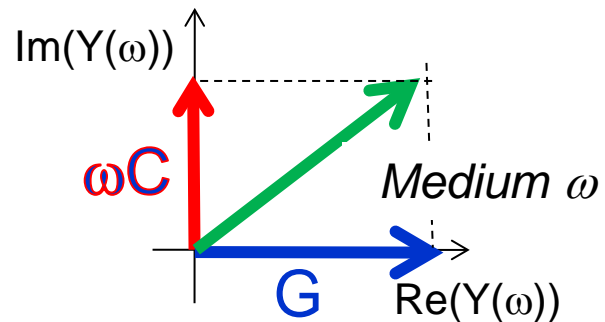
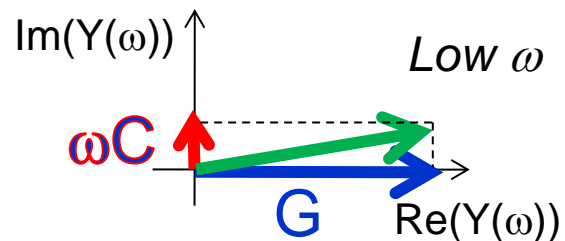
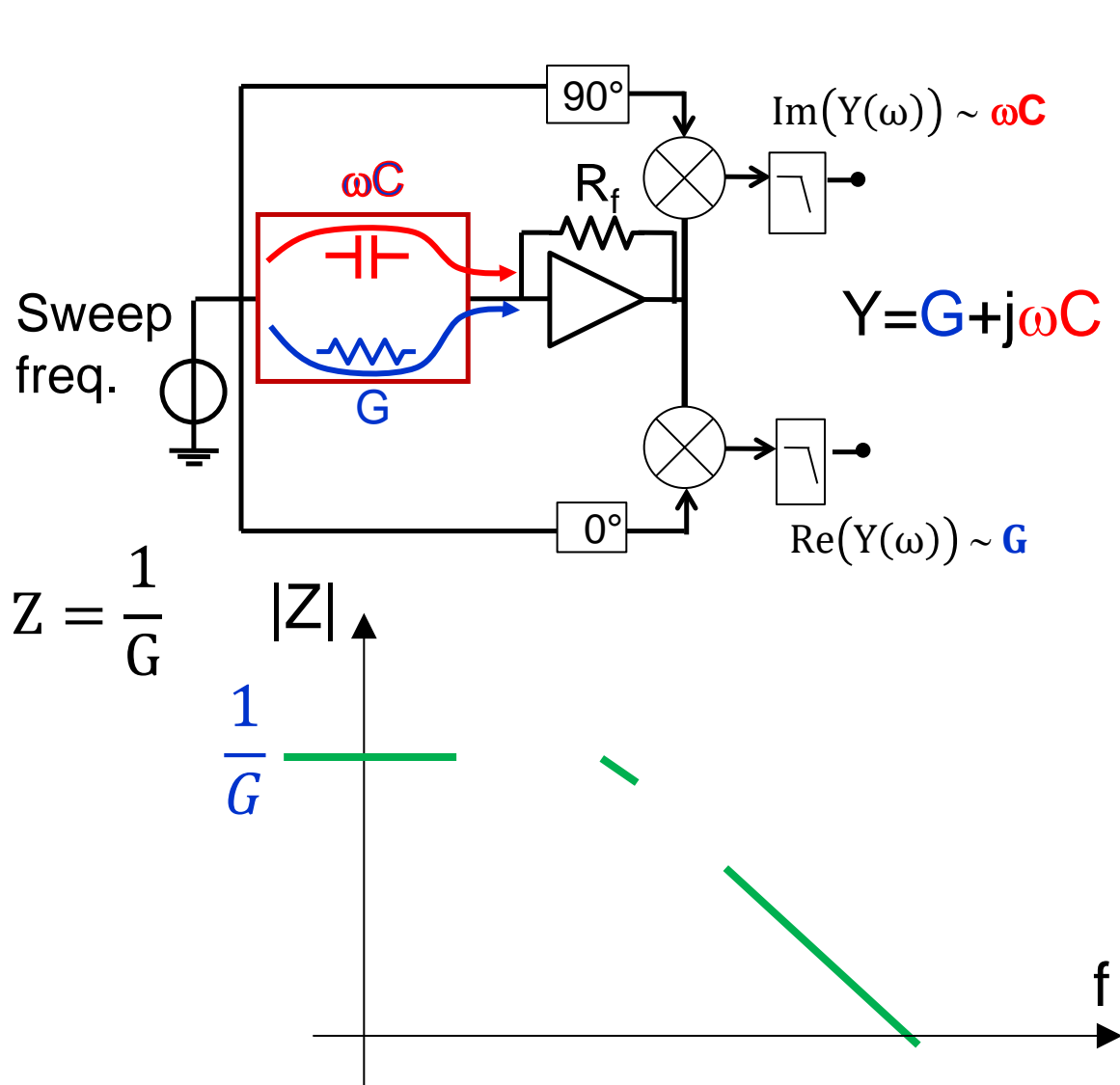


Lock-In: Impedance of R||C





Sweeping the frequency : spectrum



Improving the resolution

You have a good set-up for the measurement of the capacitance of a DUT based on a lock-in platform. Using $V_p = V_{ref} = 0.1V$ and by averaging the measurement for $T_m = 30ms$, you obtain a resolution of $\Delta C = 12aF$ in the sensor.

If a $\Delta C = 1aF$ is required, what will you do?

Extend the measuring time

$$\Delta C \propto \frac{1}{\sqrt{T_m}}$$

$$T_m = 30ms \quad \Rightarrow \quad T_m = 4.3s$$

Increase the amplitude of V_p or V_{ref} or both

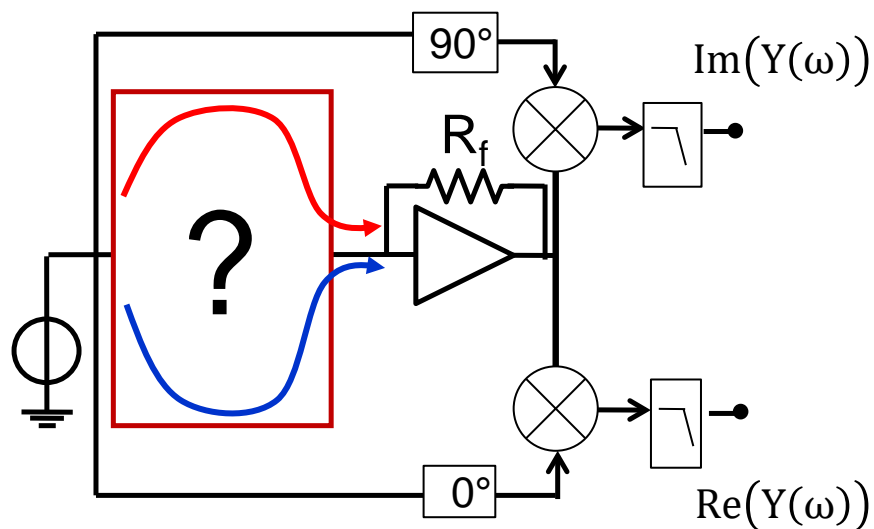
$$\Delta \omega C \propto \frac{1}{R_f V_p V_{ref}}$$

$$V_{ref} = 0.1V \quad \Rightarrow \quad V_{ref} = 1.2V$$

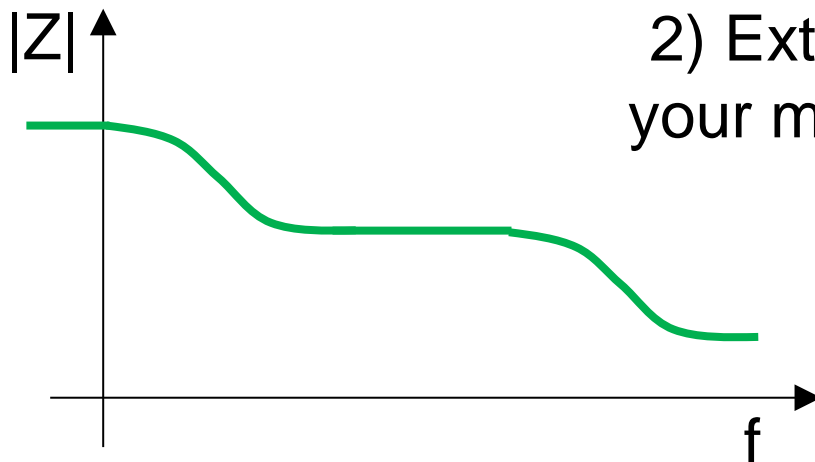


Extracting elements from a spectrum

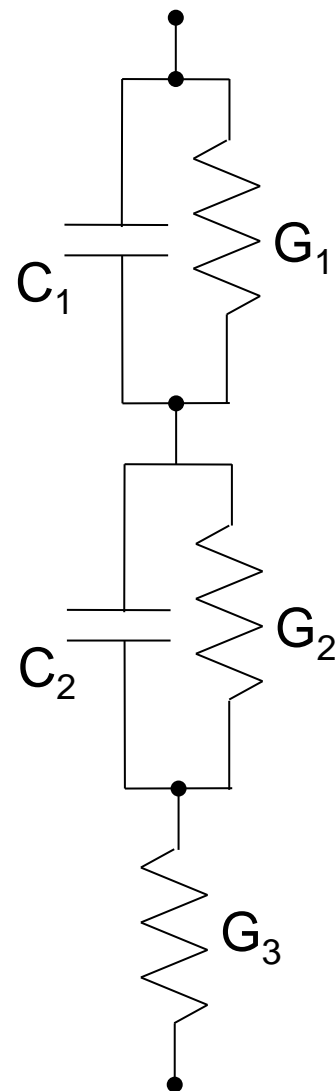
What is inside my device ?



1) Measure at different frequencies



2) Extract your model

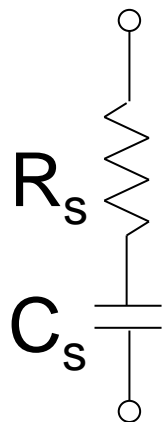




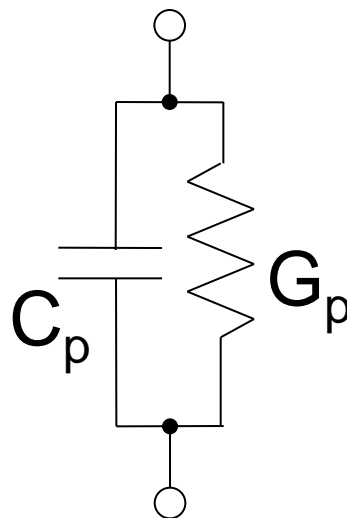
Pre-defined models in LCR meters



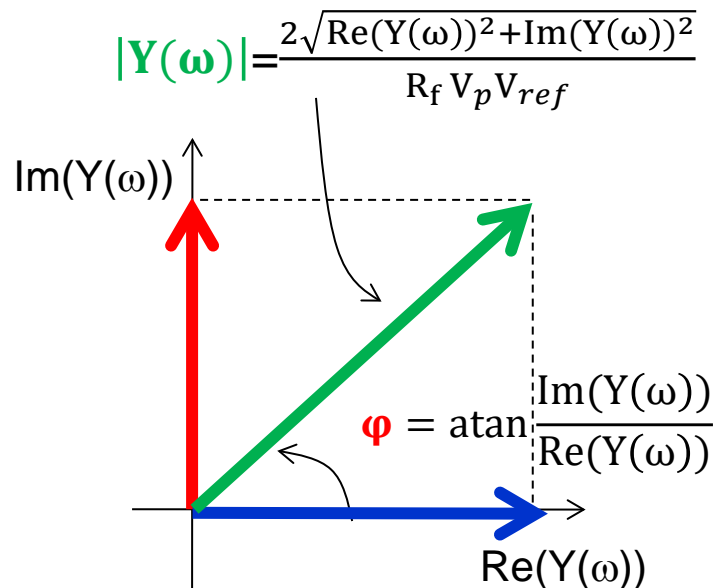
You select the model.
The instrument gives you the R & C values



$$Z(\omega) = R_s + \frac{1}{j\omega C_s}$$



$$Y(\omega) = G_p + j\omega C_p$$

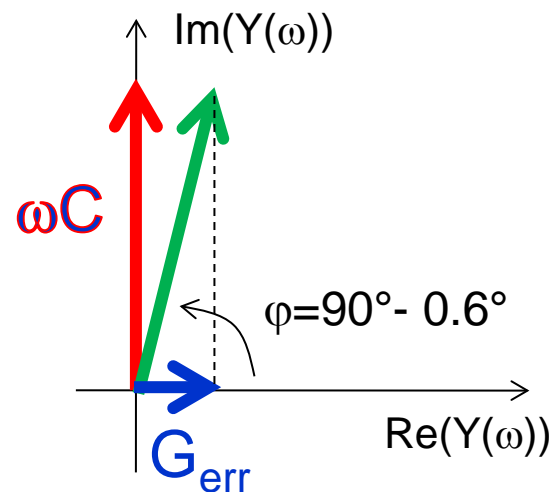
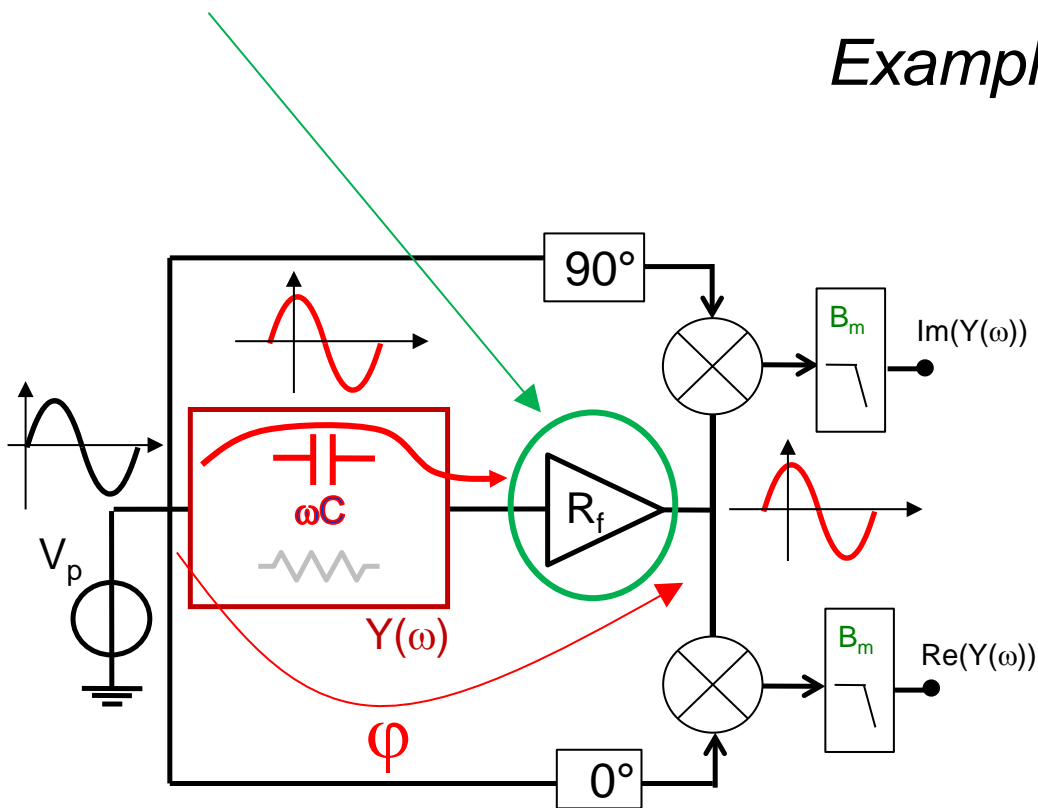




Calibration

Amplifiers and connections introduce errors in amplitude and phase

Example: $C=1\text{pF}$ at 1MHz
Phase error 0.6°
(a pole distant two decades)



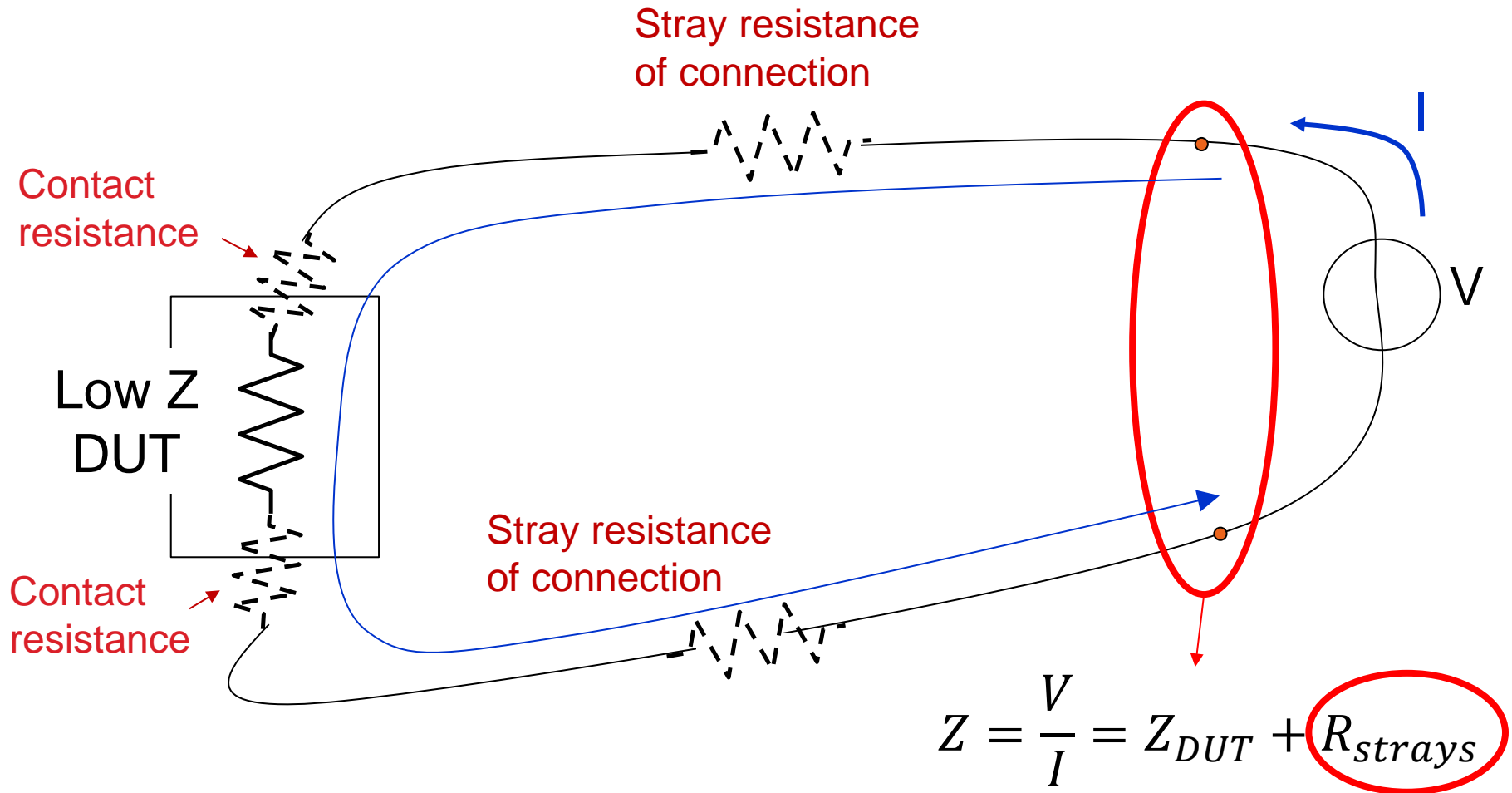
Ideal calibration: with a known sample (amplitude and phase)

$$G_{\text{err}} = \omega C_x \sin(0.6^\circ) = 6 \cdot 10^{-8} \text{ S} \\ (16\text{M}\Omega, \text{ to be compared with } \infty)$$

If $\varphi_{\text{err}}=10^\circ$ than $1/G_{\text{err}}=1\text{M}\Omega$!

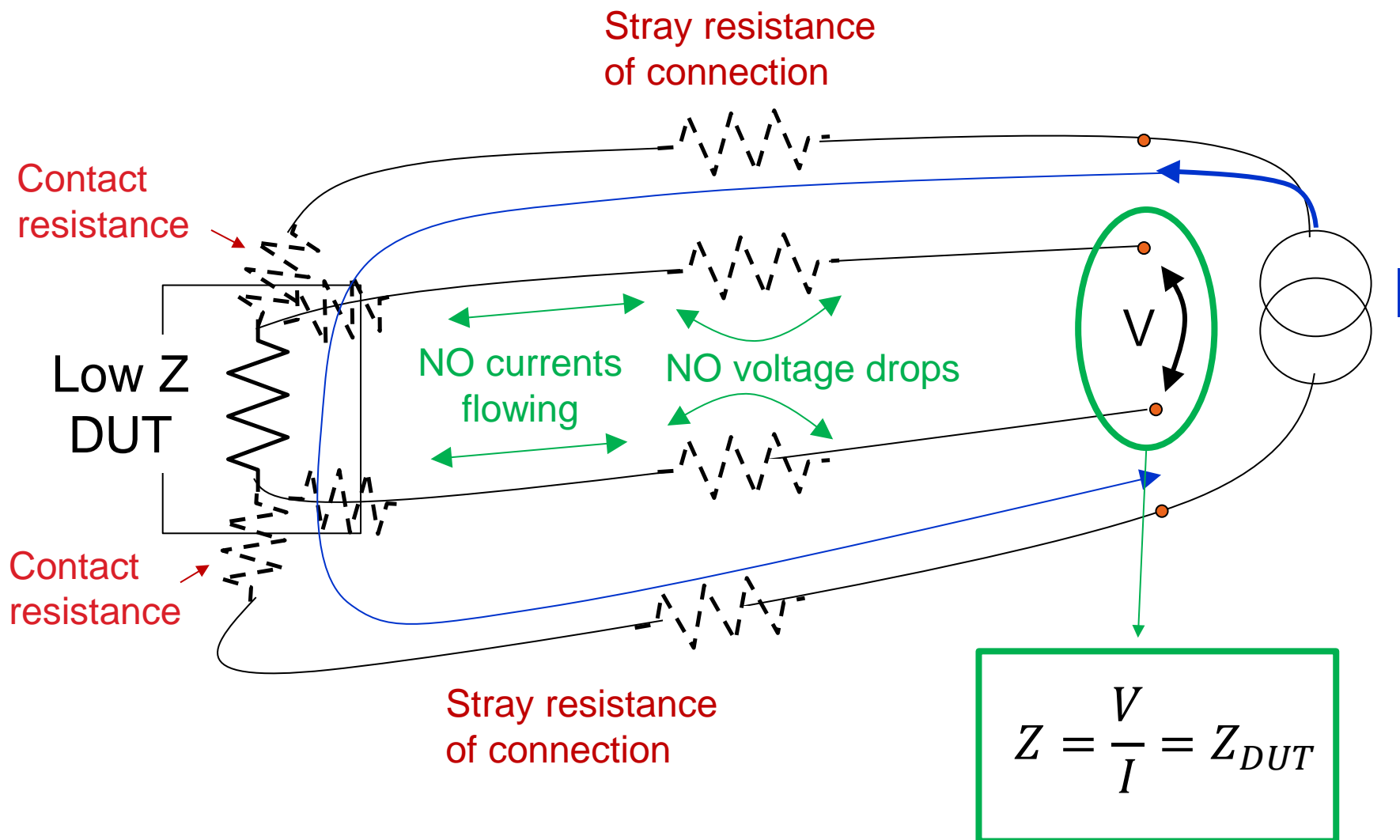


Contribution of strays (resistances)



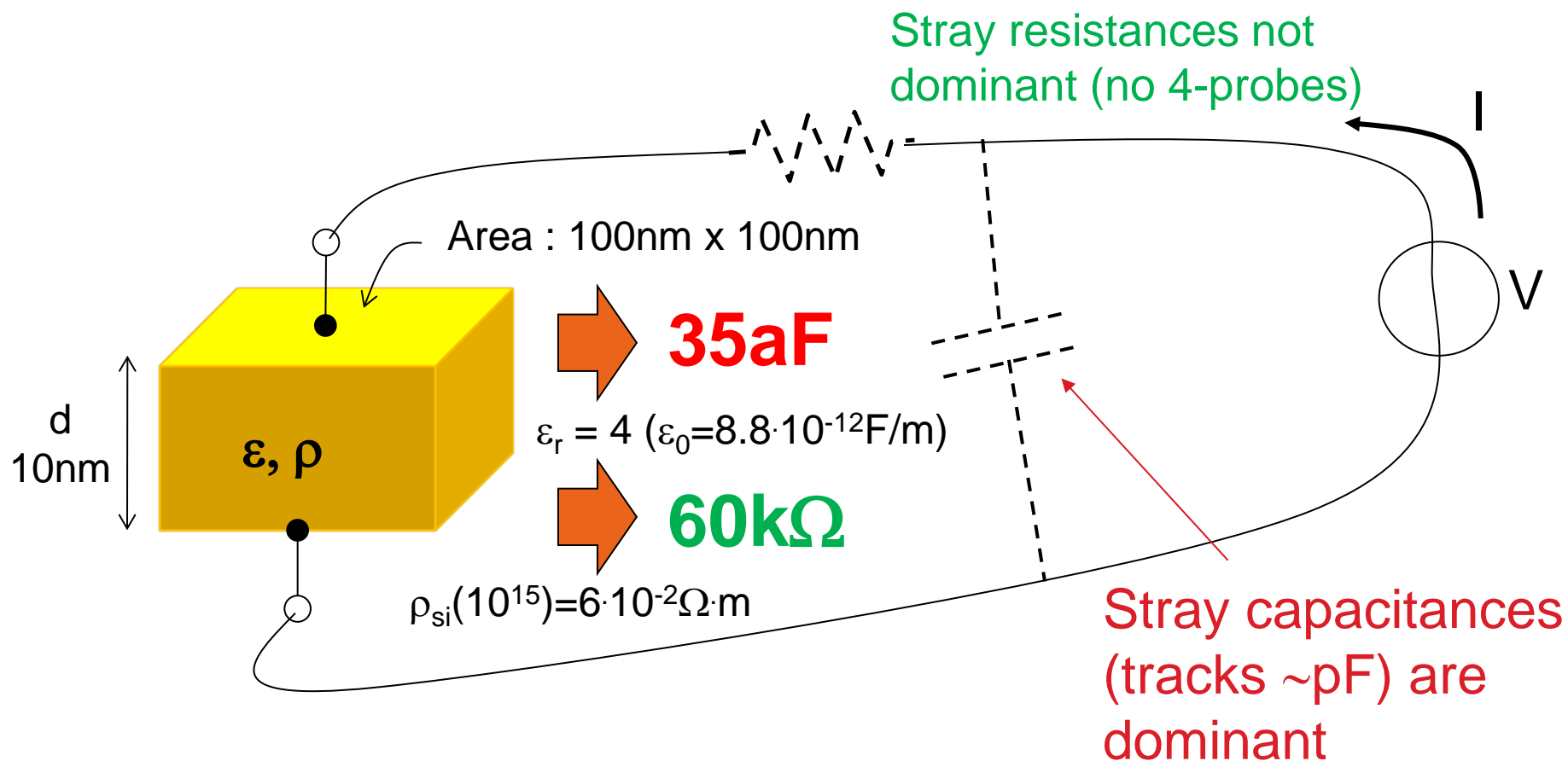


4 probes Impedance measurement





Impedance at the Nanoscale

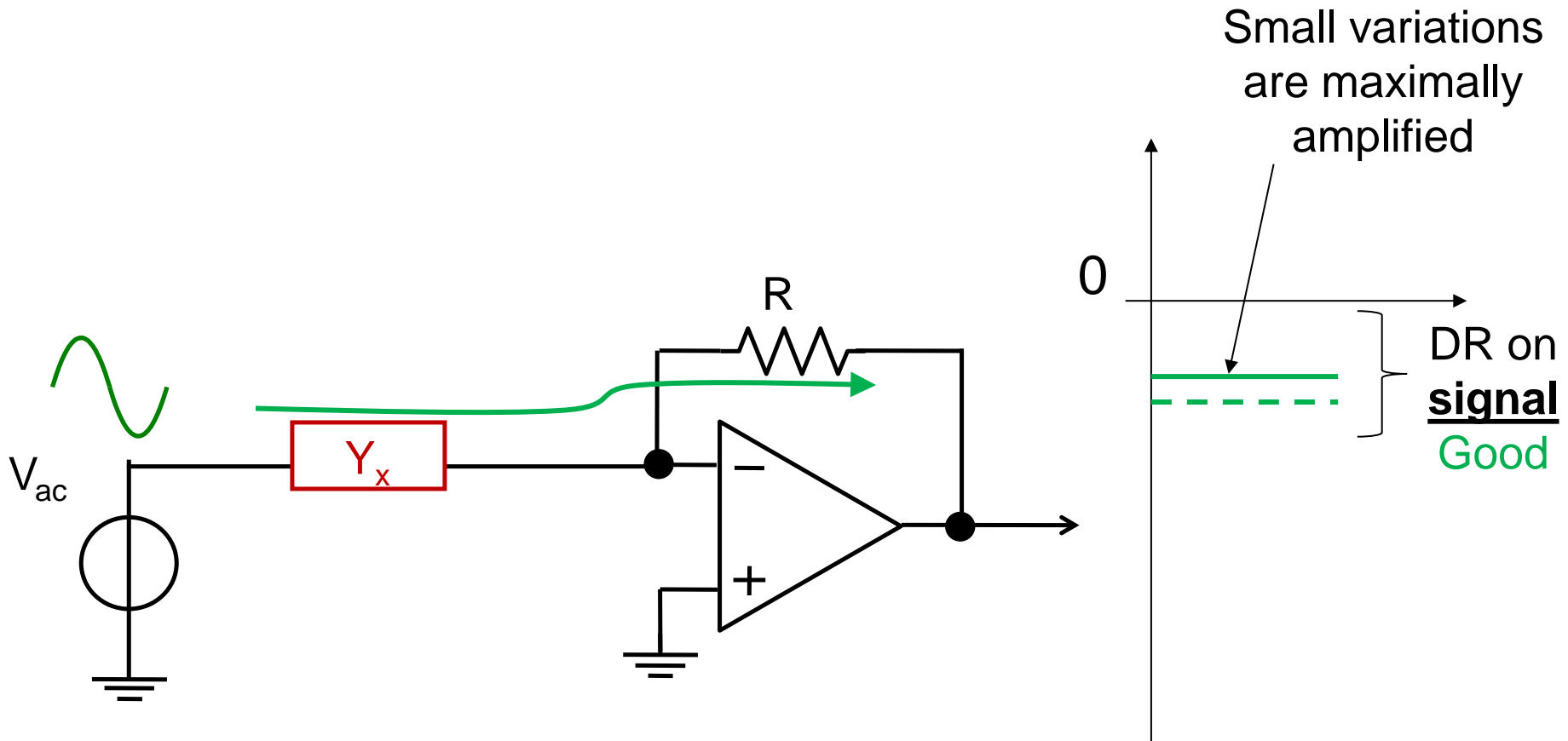


$$\tau = RC = \rho \frac{d}{\text{Area}} \cdot \epsilon \frac{\text{Area}}{d}$$

$$\tau = \rho \cdot \epsilon = 2\text{ps} \text{ *independent* of size}$$



Problems given by strays (capacitance)



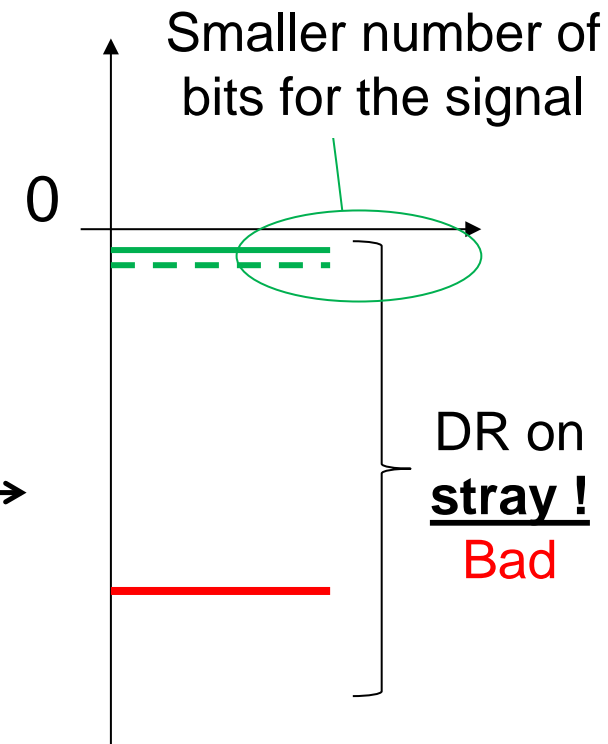
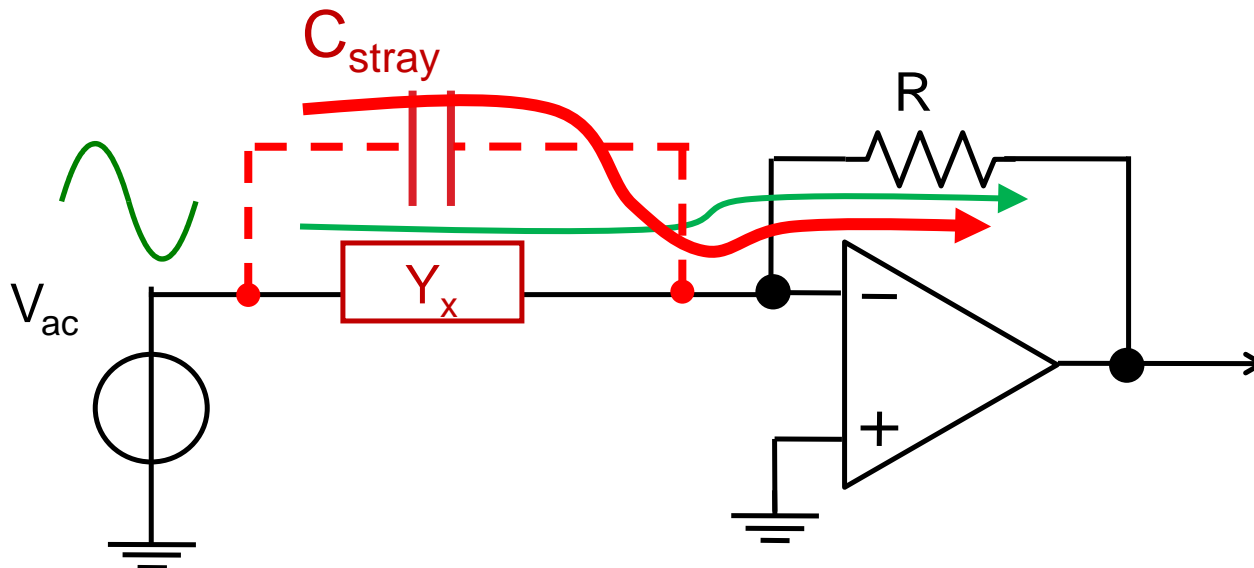
Reduction of sensitivity

A stray parallel capacitance C_{stray} may:

- saturate the front-end or gain stages

➔ Reduce gain \Rightarrow reduce resolution

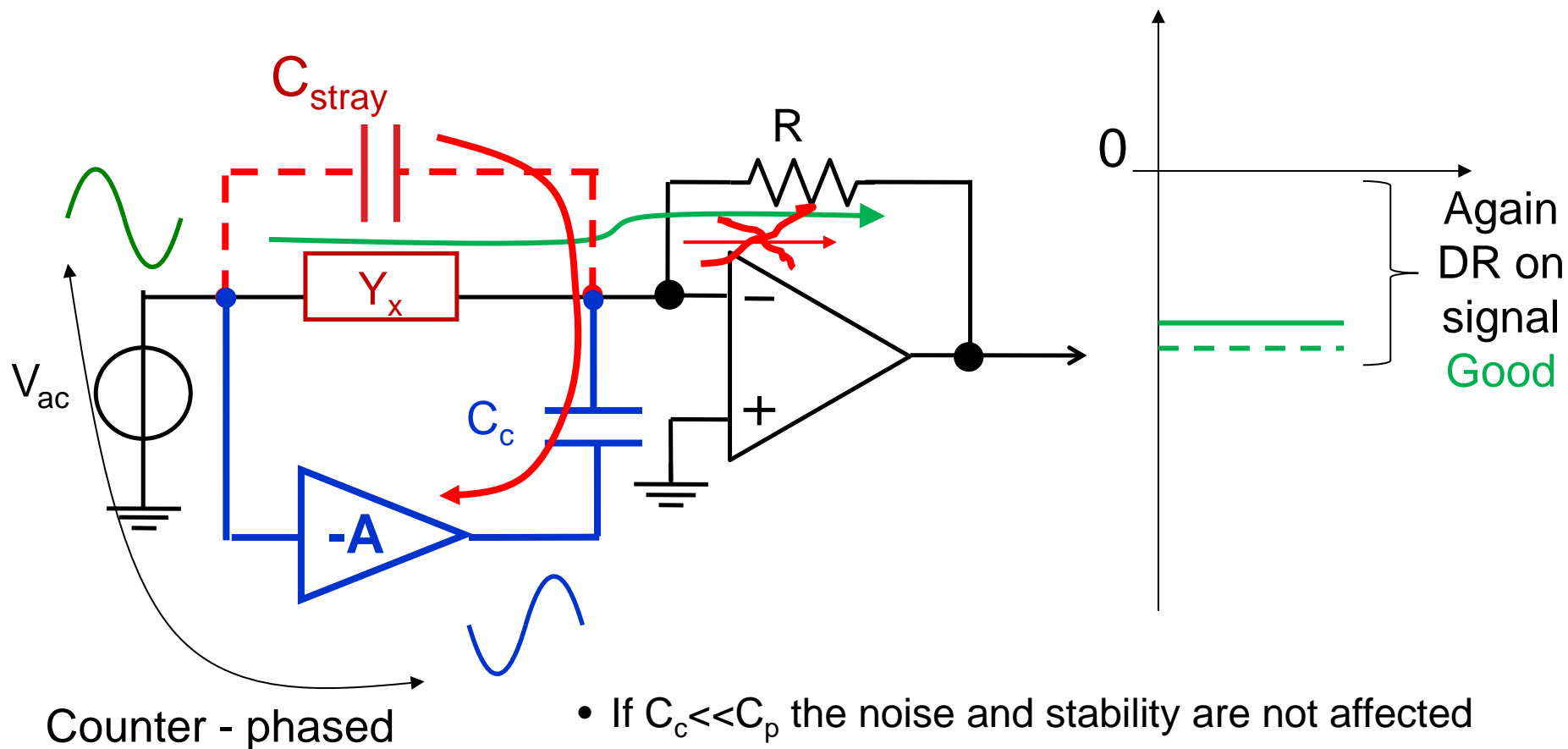
- require ADC with large bit number





Compensation in current sensing

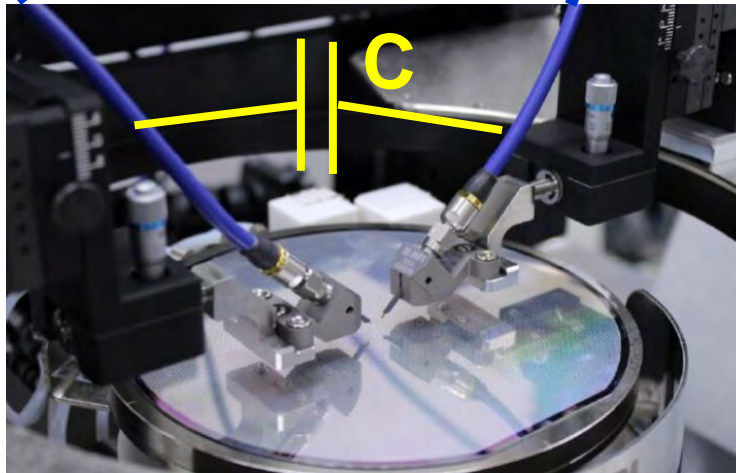
An **active capacitance compensation** can be useful:



- If $C_c \ll C_p$ the noise and stability are not affected
- Calibration required



Strays compensation in LCR meter (1)

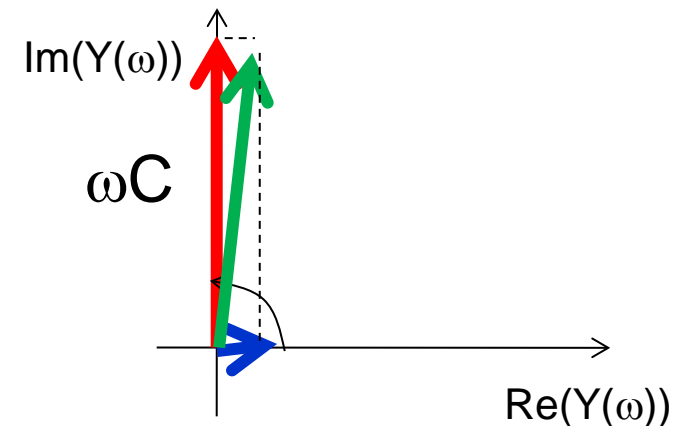


OPEN

You Lift the probes (a little)

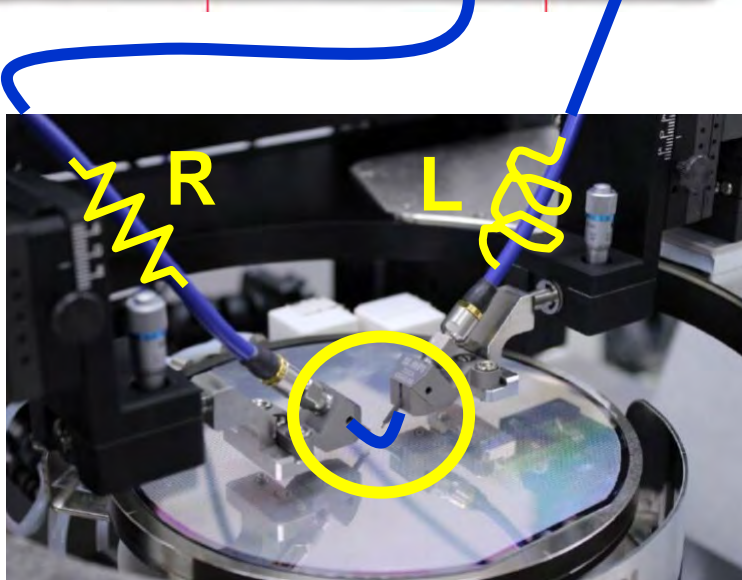
The instrument :

- Measures (the strays, mainly capacitance)
- Memorizes the values Re and Im at different f
- Correct the following meas. with these values





Strays compensation in LCR meter (2)

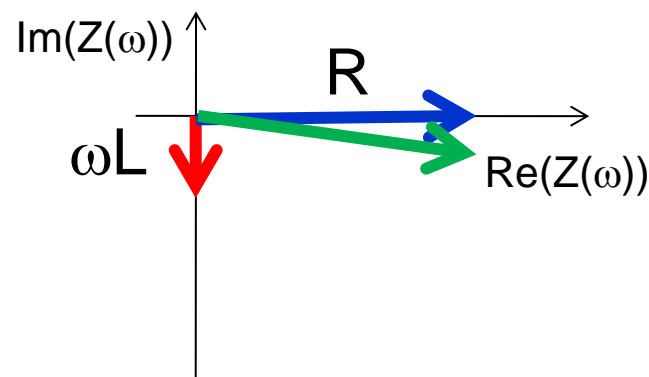


SHORT

You Put probes in contacts

The instrument

- Measures (the strays, mainly resistance-inductance)
- Memorizes the values Re and Im at different f
- Correct the following meas. with these values

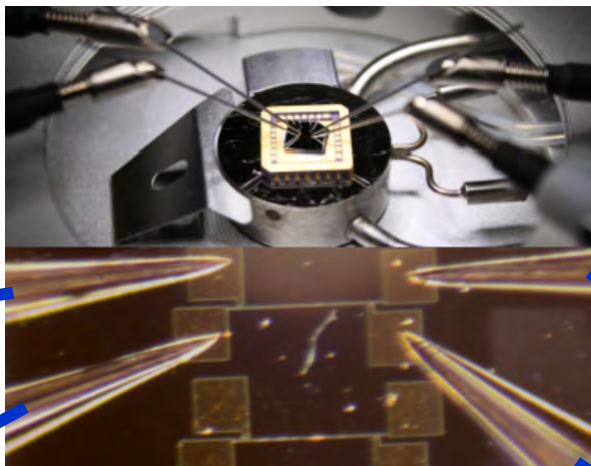




Strays compensation in LCR meter (3)



In addition USE 4 PROBES

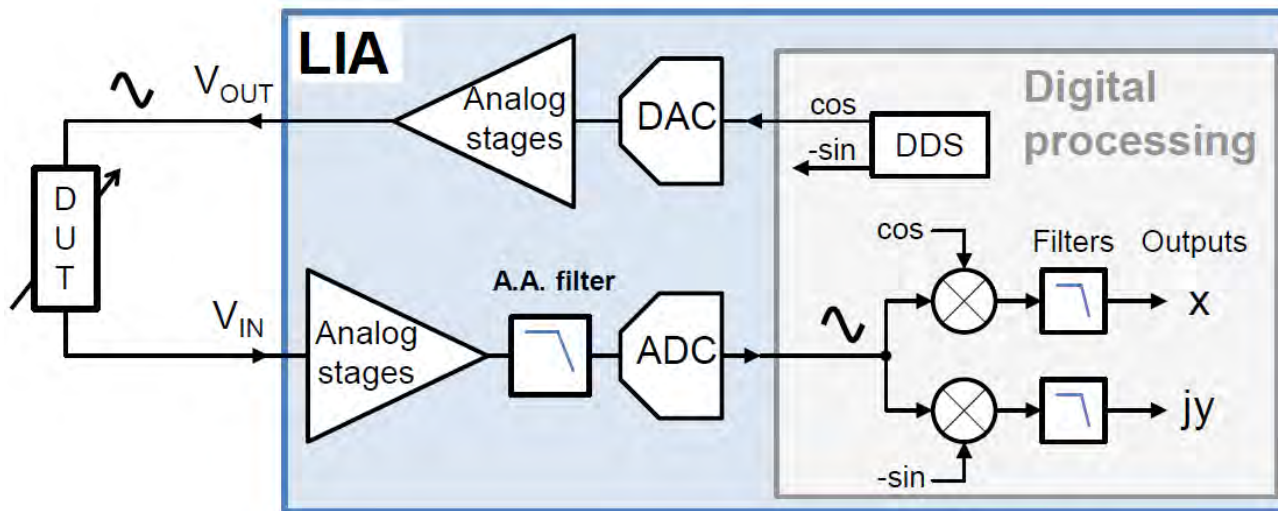




Digital LOCK-IN amplifiers

Impedance spectroscopy with lock-in requires a separate measurement for each frequency → **long time**

Alternatives : Apply many-frequencies as stimulus and process in parallel;
Apply white noise at input and calculate the DFT of signals.



Next lesson
by Giorgio
Ferrari



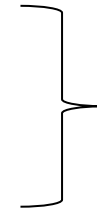
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Bridge Circuit

Oscilloscope and Function Generator using the voltage-divider principle

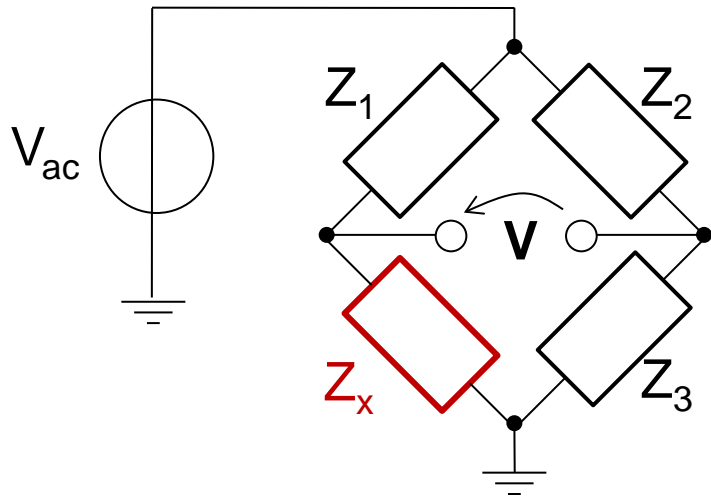


Lock-in
architecture

Material follows for your convenience



Balancing Bridge: Working Principle

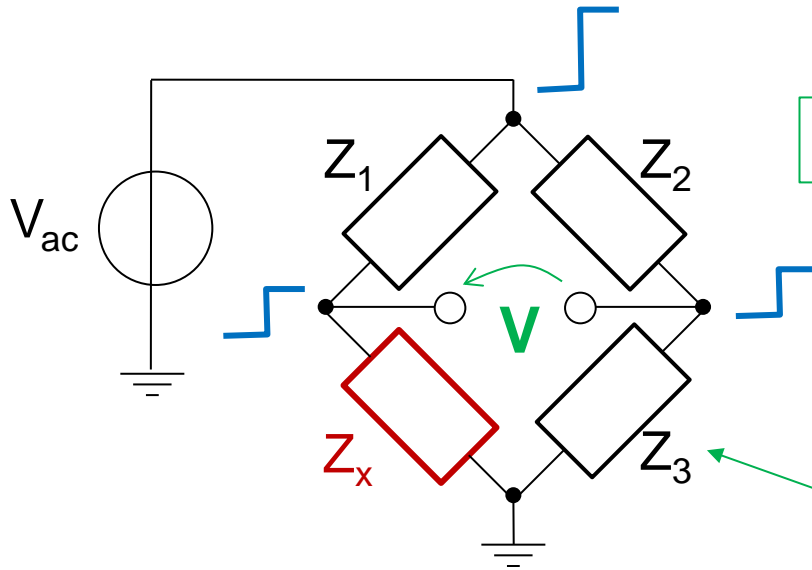


- Z_1, Z_2, Z_3 known and variable (switches)
- V_{ac} sinusoidal

$$V = V_{ac} \left(\frac{\mathbf{Z}_x}{Z_1 + \mathbf{Z}_x} - \frac{Z_3}{Z_2 + Z_3} \right)$$

Balanced for $V = 0 \Rightarrow \mathbf{Z}_x = Z_3 \frac{Z_1}{Z_2}$

Bridge Pros and Cons



Pros:

Voltage reader operates always with $V \approx 0V$

Common mode rejection

Good accuracy (no active stages, depends on the accuracy of the reference impedances)

Cons:

- Requires several switches
- Slow balancing routine
- Not very convenient for spectroscopy

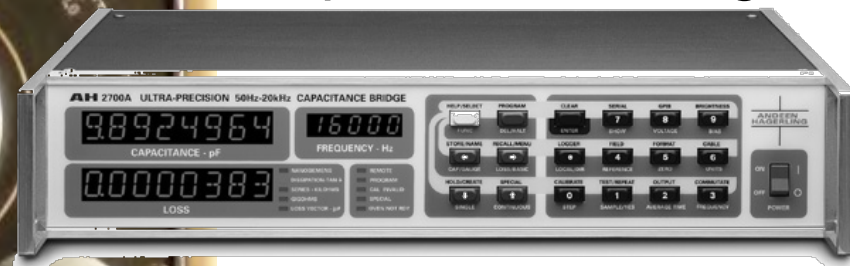


Examples of Commercial Instruments

GR 1650-A (1957) ...fully manual



Andeen-Hagerling
AH 2700A
50Hz-20kHz
Capacitance Bridge

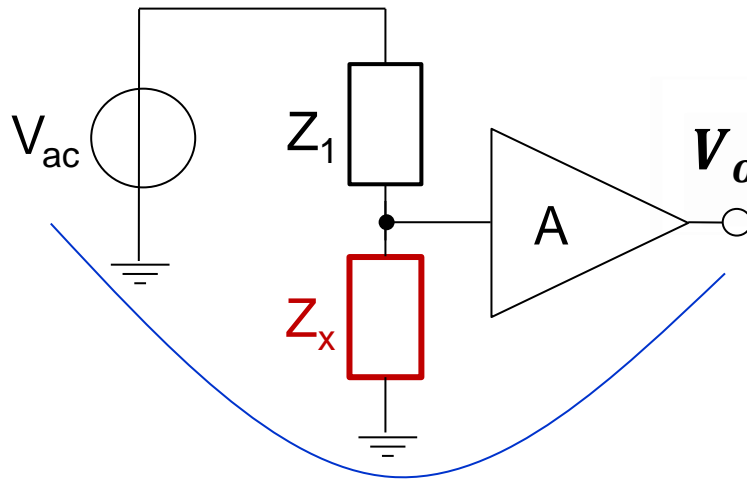


0.5aF, 1PΩ resolution

↘ Ratiometric: Half Bridge

Ratiometric i.e. V_{out} depends on the impedance ratio

↓
Independent of the absolute value



$$V_{out} = V_{ac} \frac{Z_x}{Z_1 + Z_x} A$$

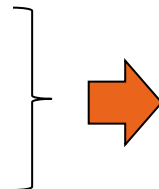
↪

$$Z_x = Z_1 \frac{V_{out}}{AV_{ac} - V_{out}}$$

A phase sensitive detector is needed

Z_1 has to be accurate (wide dynamic) :

- $Z_x \gg Z_1$: $V_{out} \approx AV_{ac}$
- $Z_x \ll Z_1$: $V_{out} \approx 0$

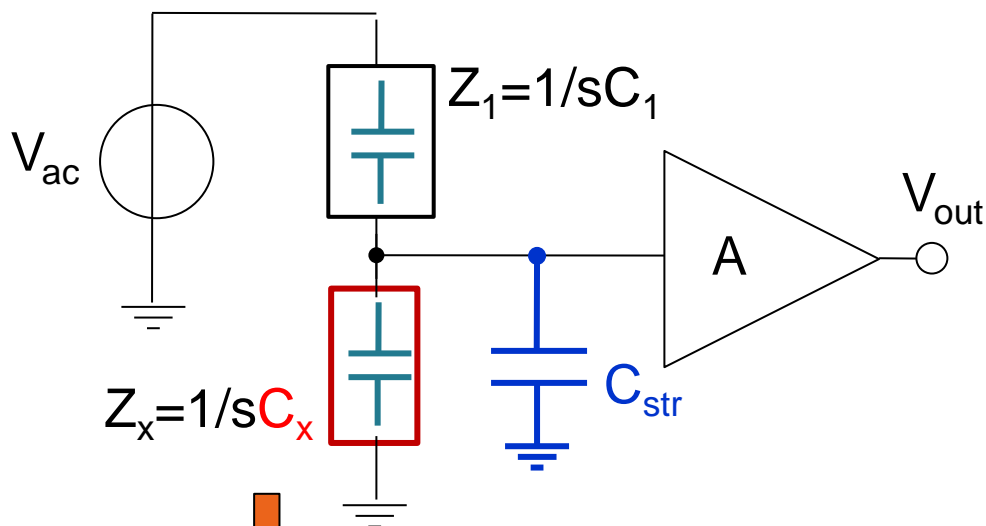


$$Z_1 \sim Z_x$$

Difficult at the
nanoscale



Capacitance detection: Effect of C_{stray}



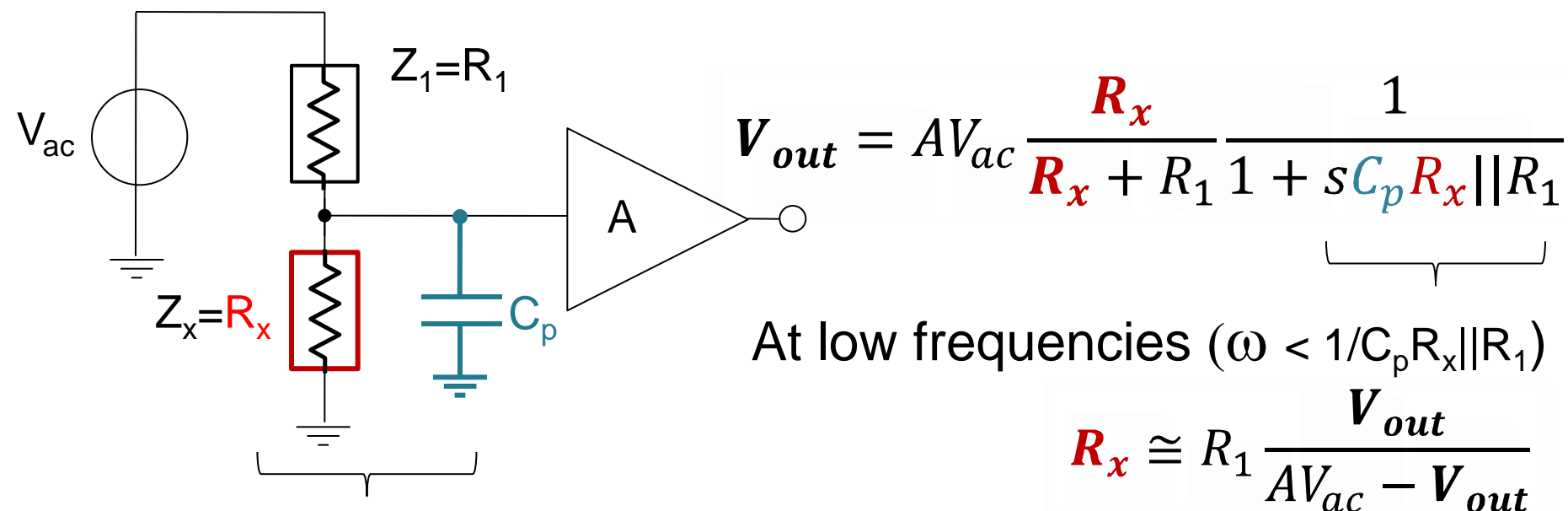
$$C_x = C_1 \frac{AV_{ac} - V_{out}}{V_{out}} - C_{str}$$

Reduces the accuracy !

DC bias of Z_x not defined



Resistance detection: Effect of C_{stray}



At high frequencies ($\omega > 1/C_p R_x || R_1$)

→ R_x shunted by C_p !

Example: a cube of intrinsic Si ($\sim 1\text{k}\Omega\text{ cm}$), side = 50nm

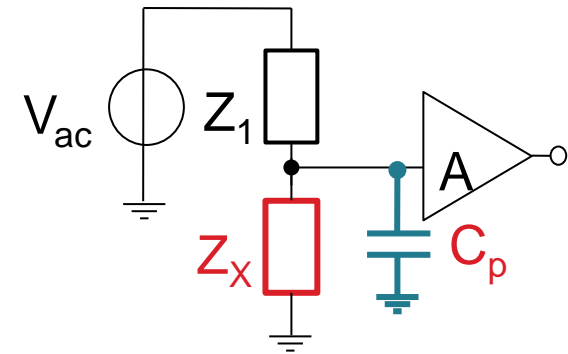
→ $R_x = 200\text{M}\Omega$, cut-off frequency = 160Hz ($C_p = 5\text{pF}$)



Comparison

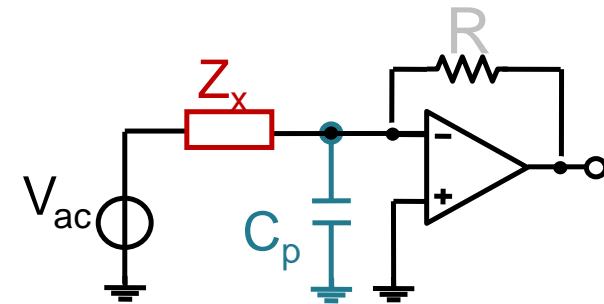
Ratiometric:

- C_p limits bandwidth and accuracy
- No control of the voltage applied to Z_x
- Z_1 must match Z_x



Current sensing:

- Independent of C_p (wide-band opamp)
- Precise control of the voltage applied
- Need to access both terminals of Z_x
- Loop stability depends on Z_x (but at the nanoscale dominated by stray capacitance \approx known)



In terms of resolution they are **equivalent**